Substitute	Form	PTO-14	49
(Modified)			

U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. 14072-006001

Application No. 09/524,027

Information Disclosure Statement
by Applicant
(Use several sheets if necessary)

Applicant Burrell et al

Group Art Unit 3761

(37 CFR §1.98(b))

Filing Date
March 13, 2000

					nt Documents			
	miner itial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
1	-	AA	2002/0045049	04/18/02	Madsen		-	
		AB	6,365,130	04/02/02	Barry et al.			
		AC	2002/0025344	02/28/02	Newman et al.			
		AD	2002/0016585	02/07/02	Sachse			
		AE	2002/0001628	01/03/02	Ito			
		AF	6,277,169	08/21/01	Hampden-Smith et al.			
		AG	2001/0010016	07/26/01	Modak et al.			
		AH	6,258,385	07/10/01	Antelman			
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		AK	6,197,351	03/06/01	Neuwirth			-
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		AQ	6,071,543	06/06/00	Thornfeldt		-	
		AR	6,071,541	06/06/00	Murad			
		AS	6,022,547	02/08/00	Herb et al.			
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		AX	5,895,419	04/20/99	Tweden et al.			
		AY	5,792,793	08/11/98	Oda et al.			
	V	AZ	5,744,151	04/28/98	Capelli			
		AAA	5,631,066	05/20/97	O'Brien			

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EXAMINER: Initials citation considered Draw line through citation if no	t in conformance and not considered. Include copy of this form with
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. •	Substitute Disclosure Form (PTO-1449)

Substitute Form PTO-1449 (Modified)

U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. 14072-006001

Applicant

Application No. 09/524,027

Information Disclosure Statement by Applicant (Use several sheets if necessary)

Burrell et al

(37 CFR §1.98(b))

Filing Date
March 13, 2000

Group Art Unit 3761

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	miner itial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
L	_	ABB	5,578,073	11/26/96	Haimovich et al.			
		ACC	5,563,132	10/08/96	Bodaness			
		ADD	5,534,288	07/09/96	Gruskin et al.			
		AEE	5,520,639	05/28/96	Peterson et al.			
		AFF	5,457,015	10/10/95	Boston			
		AGG	5,399,163	03/21/95	Peterson et al.			
		АНН	5,383,851	01/24/95	McKinnon, Jr. et al.			
		AII	5,369,155	11/29/94	Asmus			
		AJJ	Des. 349,958	08/23/94	Hollis et al.		1	
		AKK	5,312,335	05/17/94	McKinnon et al.			
		ALL	5,270,358	12/14/93	Asmus			
		AMM	5,143,717	09/01/92	Davis			
		ANN	5,122,418	06/16/92	Nakane et al.			
		AOO	5,064,413	11/12/91	McKinnon et al.			
		APP	5,019,096	05/28/91	Fox, Jr. et al.			
		AQQ	4,960,413	10/02/90	Sagar et al.			
		ARR	4,952,411	08/28/90	Fox, Jr. et al.			
		ASS	4,847,049	07/11/89	Yamamoto			
		ATT	4,803,066	02/07/89	Edwards			
		AUU	4,790,824	12/13/88	Morrow et al.			
		AVV	4,749,572	06/07/88	Ahari			
	_	AWW	4,596,556	06/24/86	Morrow et al.			
		AXX	4,581,028	04/08/86	Fox, Jr. et al.			
		AYY	4,476,590	10/16/84	Scales et al.			
		AZZ	4,355,636	10/26/82	Oetjen et al.			
		AAAA	3,800,792	04/02/74	McKnight et al.			
	2	ABBB	3,757,786	09/11/73	Smith			

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Substitute Form PTO-1449 U.S. Department of Commerce Attorney's Docket No. Application No. Patent and Trademark Office (Modified) 14072-006001 09/524,027 Applicant **Information Disclosure Statement** Burrell et al by Applicant (Use several sheets if necessary) Filing Date Group Art Unit March 13, 2000 3761 (37 CFR §1.98(b))

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Examiner	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Trans Yes	slation No
Initial			06/06/02	WIPO	Class	Subciass	168	140
	ACCC	02/44625						
<u> </u>	ADDD	02/18003	03/07/02	WIPO				
h	AEEE	02/18699	03/07/02	WIPO			ļ. <u></u>	
<u>_</u>	AFFF	02/15698	02/28/02	WIPO				
	_AGGG	CN1328819	01/02/02	CN (full document)				X-
L	АННН	CN1328819	01/02/02	CN (abstract only)			X	
-		CN1328827	01/02/02	CN (full document)				X
	AJJJ	CN1328827	01/02/02	CN (abstract only)			X	
١	AKKK	1 159 972	12/05/01	EP				
	ALLL	CN1322474	11/21/01	CN (full document)				-X,
I	AMMM	CN1322474	11/21/01	CN (abstract only)			X	
	ANNN	CN1322874	11/21/01	CN (full document)				X
<u></u>	A000	CN1322874	11/21/01	CN (abstract only)			X	
٠, ٢	APPP	01/74300	10/11/01	WIPO				
L	AQQQ	01/70052	09/27/01	WIPO				
	ARRR	CN1306117	08/01/01	CN (full document)				X
	ASSS	CN1306117	08/01/01	CN (abstract only)			X	
F	ATTT	01/49115	07/12/01	WIPO			_	
4	AUUU	01/49302	07/12/01	WIPO				
	AVVV	01/43788	06/21/01	WIPO				
	AWWW	01/41819	06/14/01	WIPO				
	AXXX	01/41774	06/14/01	WIPO				
\bigvee	AYYY	01/34686	05/17/01	WIPO				
7	AZZZ	01/27365	04/19/01	WIPO				
	- ^^^	CN1291666	04/18/01	CN (full document)				X
7	ABBBB	CN1291666	04/18/01	CN (abstract only)			X	
	_ACCCC	CN1291667	04/18/01	CN (full document)				X

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EXAMINER: Initials citation considered. Draw line through citation if n	ot in conformance and not considered. Include copy of this form with

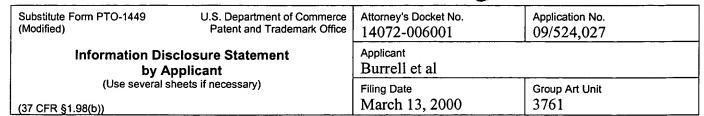
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Substitute Form PTO-1449 U.S. Department of Commerce Attorney's Docket No. Application No. (Modified) Patent and Trademark Office 14072-006001 09/524,027 **Applicant Information Disclosure Statement** Burrell et al by Applicant (Use several sheets if necessary) Filing Date Group Art Unit March 13, 2000 3761 (37 CFR §1.98(b))

	Foreig	n Patent Doo	uments or P	ublished Foreign I	Patent A	Application	ns	
Examiner	Desig.	Document	Publication	Country or	01	0 1 - 1 - 1		slation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
<u> </u>	ADDDD		04/18/01	CN (abstract only)			X	
<u> </u>	AEEEE	01/24839	04/12/01	WIPO	ļ			
<u></u>	AFFFF	01/15710	03/08/01	WIPO				
_	AGGGG	CN1279222	01/10/01	CN (full document)				X
h	АНННН	CN1279222	01/10/01	CN (abstract only)			X	
7	AIIII	00/78282	12/28/00	WIPO				
L	AJJJJ	00/64505	11/02/00	WIPO		-		
L	AKKKK	00/64506	11/02/00	WIPO				
)	ALLLL	CN1262093	08/09/00	CN (full document)				X
<u> </u>	AMMMM	CN1262093	08/09/00	CN (abstract only)			X	
L	ANNNN	00/44414	08/03/00	WIPO				
<u>لـ</u>	A0000	00/30697	06/02/00	WIPO				
	АРРРР	CN1241662	01/19/00	CN (full document)				X —
	AQQQQ	CN1241662	01/19/00	CN (abstract only)			X	
h	ARRRR	98/51273	11/19/98	WIPO				
<u></u>	ASSSS	0 599 188	06/01/94	EP				
	ATTTT	CN1082645	02/23/94	CN (full document)				X
<u></u>	AUUUU	CN1082645	02/23/94	CN (abstract only)			Х	
_	AVVVV	92/13491	08/20/92	WIPO				
	AWWWW	022309	12/06/90	IT (full document)	· 6			X
L	AXXXX	022309	12/06/90	IT (full translation)			Х	
h	AYYYY	0 378 147	07/18/90	EP				
L	AZZZZ	0 355 009	02/21/90	EP				
h	ААААА	0 356 060	08/07/89	EP				
h	ABBBBB	0 254 413	01/27/88	EP				
	ACCCCC	87/07251	12/03/87	WIPO				
1—	ADDDDD	0 136 768	04/10/85	EP				

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Substitute Disclosure Form (PTO-1449)



	Foreig	n Patent Doc	uments or P	ublished Foreign F	Patent A	Application	ns	
Examiner	Examiner Desig. Document			Country or			Trans	slation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AEEEEE	60-21912	02/04/85	JP (full document)			ļ	X
	AFFFFF	60-21912	02/04/85	JP (abstract only)			X	
	AGGGGG	Sho 58-	02/04/85	JP (full document)				X
	A00000	126910	02/04/85	Ji (luli document)				<u>^</u>
	АНННН	Sho 58- 126910	02/04/85	JP (abstract only)			x	
<u>L</u>	AIIII	2 140 684	12/05/84	UK				
1	AJJJJJ	2 073 024	10/14/81	UK				
	AKKKKK	965,010	07/29/64	GB				
L 6	ALLLLL	427,106	04/16/35	UK				
	АММММІ	420,052	11/23/34	UK				

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L	ANNNNN	Shigemasa et al., "Applications of Chitin and Chitosan for Biomaterials" <i>Biotechnology & Genetic Engineering Reviews</i> Vol. 13 (14) pp. 383-420							
L	A00000	Thornton, "Deposition Technologies for Films and Coatings: Coating Deposition by Sputtering" Materials Science Series 5 pp. 170-243 1982							
	APPPPP	Thornton, "Influence of apparatus geometry and deposition conditions on the structure and topography of thick sputtered coatings" J. Vac. Sci. Technol., Vol. 11, No. 4, July/Aug. 1974							

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U.S. Department of Commerce Patent and Trademark Office

Patent and Trademark Office

Attorney's Docket No. 14072-006001

Application No. 09/524,027

Applicant

Burrell et al

Filing Date

(37 CFR \$140(b))

Group Art Unit

March 13, 2000

Application No. 09/524,027

Application No. 14072-006001

Application N

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1	AB	2002/0051824 A1	05/02/02	Burrell et al.	424	(4)	TECK.
	AC	6,333,093	12/25/01	Burrell et al.	428	194 ECK	APR STU
	AD	6,238,686	05/29/01	Burrell et al.	424	423	OLOGY CENTERRISTO
	AE	6,017,553	01/25/00	Burrell et al.	424	405	CENT
	AF	5,985,308	11/16/99	Burrell et al.	924	426	CAR3>
	AG	5,958,440	09/28/99	Burrell et al.	424	409	
	AH	5,848,995	12/15/98	Walder	1204	245	
	AI	5,837,275	11/17/98	Burrell et al.	424	409	
	AJ	5,770,258	06/23/98	Takizawa	427	64	
	AK	5,753,251	05/19/98	Burrell et al.	424	424	
V	AL	5,681,575	10/28/97	Burrell et al.	424	423	
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Examiner Initial	Desig. ID	Document Number	Publication	Country or				slation
1			Date	Patent Office	Class	Subclass	Yes	No
1	AN	02/09729	02/07/02	WIPO				
	AO	01/80920	11/01/01	WIPO				
V	AP	01/68179 A1	09/20/01	WIPO		···		
L'	AQ	01/49301	07/12/01	WIPO				
	AR	2000327578	11/28/00	JP (full document)				X_
M .	A.S	200032 75 78 -	11/28/00	JP (abstract only)	- L		X	-
<u> </u>	AT	00/27390	05/18/00	WIPO				
<u>ا</u>	AU	0 328 421 A2	08/16/99	EP				
	AV	11124335	05/11/99	IP (full document)				X
ا ا	ΑŴ	11124335	05/11/99	JP (abstract only)			X	
	AY	11116488	04/27/99	JP (full document)				X

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U.S. Department of Commerce Patent and Trademark Office Substitute Form PTO-1449 Attorney's Docket No. Application No. 14072-006001 09/524,027 দ্ধি rmation Disclosure Statement Applicant by Applicant
(Use several sheets if necessary) Burrell et al Filing Date Group Art Unit 37621 March 13, 2000

GIRADEMA	Foreig	n Patent Doo	ruments or P	ublished Foreign	Patent A	Application	ne	
Examiner	Desig.	Document	Publication	Country or	T dtont /	Application	Translation	
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
-	AY	11116488	04/27/99	JP (abstract only)			X 🔊	
	AZ	11060493	03/02/99	JP (full document)		λ.	4.	
<u></u>	AAA	11060493	03/02/99	JP (abstract only)		CHN		(V)
L	ABB	98/41095	09/24/98	WIPO			OGY	12
سسا	ACC	0681841	11/15/95	EP			CEN	TO 3
	ADD	95/13704	05/26/95	WIPO			\	A ASTON
~	AEE	93/23092	11/25/93	WIPO				00

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L	AFF	Sant et al., "Morphology of Novel Antimicrobial Silver Films Deposited By Magnetron Sputteri Scripta Materiala, Vol. 41, No. 12, pp. 1333-1339, November 19, 1999					

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